



BSI Standards Publication

Semiconductor devices — Non-destructive recognition criteria of defects in silicon carbide homoepitaxial wafer for power devices

Part 3: Test method for defects using photoluminescence

National foreword

This British Standard is the UK implementation of IEC 63068-3:2020.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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